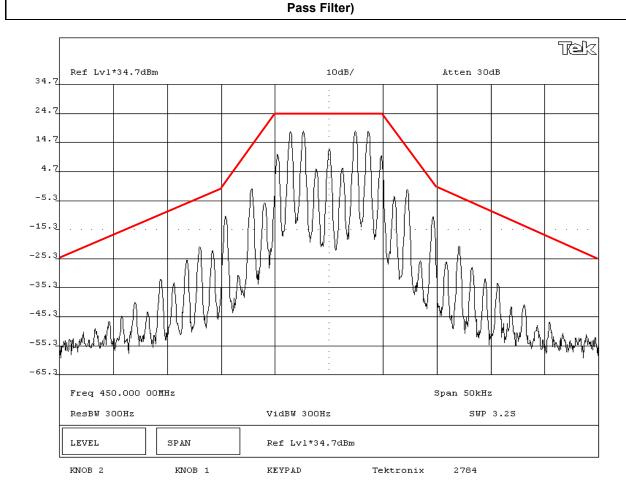
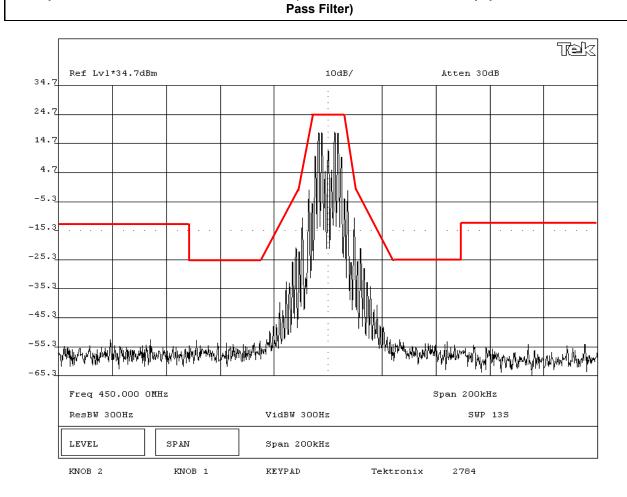
EXHIBIT J – Occupied Bandwidth Data

FCC ID# NMEAVTS1030

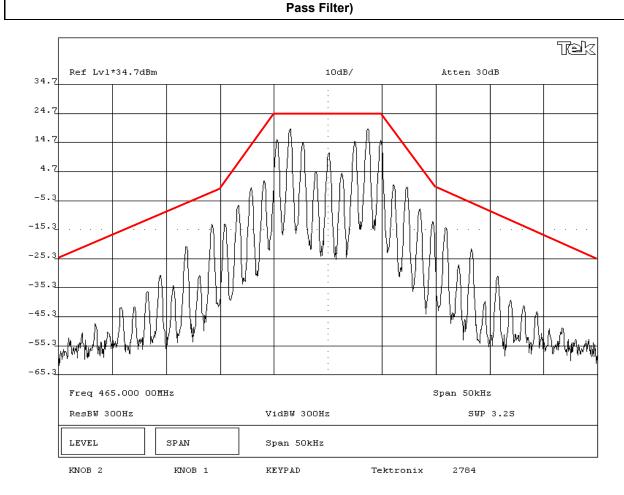
NORTHWEST		EMICOLONIC	DATA OLU					
EMC		EMISSIONS I	DATA SHI	EEI		Rev BETA 01/30/01		
	Alarm View				Work Order:	DATC0007		
Serial Number	ENG1126				Date:	06/13/01		
Customer	Data Critical Corporation				Temperature:	75 degrees F		
Attendees	N/A		Tested by:	Greg Kiemel	Humidity:	38% RH		
Customer Ref. No.:	N/A		Power:	N/A	Job Site:	EV06		
TEST SPECIFICATIONS	S							
Specification	47 CFR 2.1049 & 90.210(c)	Year: Most Current	Method:	TIA/EIA-603	Year:	1993		
SAMPLE CALCULATIO	INS							
COMMENTS								
Baseline test of unit as	received.							
EUT OPERATING MOD	ES							
Modulated at 2400 Bau	ud.							
DEVIATIONS FROM TE	ST STANDARD							
None								
REQUIREMENTS	REQUIREMENTS							
The power of any emis	sion must be attenuated below th	e specified emission mask. The 0 dB	reference for the emissi	on mask is the meas	sured output power of 24.7	dBm		
RESULTS			AMPLITUDE					
Pass								
SIGNATURE								
	AMU.K.	P						
Tested By:	79							
DESCRIPTION OF TEST	Т							
Occupied Bandwidth at Low Channel - Mask C (25 kHz Channel Bandwidth Equipment w/o Audio Low								



NORTHWEST		EMICOIONO	DATA OLU			
EMC		EMISSIONS	DATA SHI	EEI		Rev BETA 01/30/01
	Alarm View				Work Order:	DATA0007
Serial Number:	ENG1126				Date:	06/13/01
Customer:	Data Critical Corporation				Temperature:	23 degrees C
Attendees:	N/A		Tested by:	Greg Kiemel	Humidity:	38% RH
Customer Ref. No.:	N/A		Power:	N/A	Job Site:	EV06
TEST SPECIFICATIONS	5					
Specification	47 CFR 2.1049 & 90.210(c)	Year: Most Current	Method:	TIA/EIA-603	Year:	1993
SAMPLE CALCULATIO	INS					
COMMENTS						
Baseline test of unit as	received.					
EUT OPERATING MOD	ES					
Modulated at 2400 Bau	ıd.					
DEVIATIONS FROM TE	ST STANDARD					
None						
REQUIREMENTS						
The power of any emis	sion must be attenuated below the	specified emission mask. The 0 dB	reference for the emiss	ion mask is the meas	ured output power of 24.7	dBm
RESULTS			AMPLITUDE			
Pass						
SIGNATURE						
Tested By:	ADU.K.P					
DESCRIPTION OF TEST	Т					
Occupied E	Bandwidth at Low Ch	nannel - Mask C (25	kHz Channel I	Bandwidth E	quipment w/o	Audio Low



NORTHWEST		ENICOIONO	DATA OUI			
EMC		EMISSIONS	DATA SHE	:E1		Rev BETA 01/30/01
	Alarm View				Work Order:	DATC0007
Serial Number	ENG1126				Date:	06/13/01
Customer	Data Critical Corporation				Temperature:	75 degrees F
Attendees	N/A		Tested by:	Greg Kiemel	Humidity:	38% RH
Customer Ref. No.:	N/A		Power:	N/A	Job Site:	EV06
TEST SPECIFICATIONS	s					
Specification	47 CFR 2.1049 & 90.210(c)	Year: Most Current	Method:	TIA/EIA-603	Year:	1993
SAMPLE CALCULATIO	DNS					
COMMENTS						
Baseline test of unit as	received					
EUT OPERATING MOD						
Modulated at 2400 Bau						
DEVIATIONS FROM TE						
None						
REQUIREMENTS						
The power of any emis	sion must be attenuated below th	e specified emission mask. The 0 dB	reference for the emissi	on mask is the meas	ured output power of 24.7	dBm
RESULTS			AMPLITUDE			
Pass						
SIGNATURE						
Tested By:	ABU.K.	P				
DESCRIPTION OF TES	T					
Occupied E	Bandwidth at Mid C	hannel - Mask C (25 k	Hz Channel B	andwidth E	quipment w/o A	ludio Low



NORTHWEST		ENTIONIONO	DATA OLIF			
EMC		EMISSIONS I	DATA SHE	:E1		Rev BETA 01/30/01
	Alarm View				Work Order:	DATA0007
Serial Number	ENG1126				Date:	06/13/01
Customer	Data Critical Corporation				Temperature:	23 degrees C
Attendees	N/A		Tested by:	Greg Kiemel	Humidity:	38% RH
Customer Ref. No.:	N/A		Power:	N/A	Job Site:	EV06
TEST SPECIFICATIONS	S					
Specification	47 CFR 2.1049 & 90.210(c)	Year: Most Current	Method:	TIA/EIA-603	Year:	1993
SAMPLE CALCULATIO	NS					
COMMENTS						
Baseline test of unit as	raceived					
EUT OPERATING MOD						
Modulated at 2400 Bau						
DEVIATIONS FROM TE						
None	OTANDAND					
REQUIREMENTS						
	sion must be attenuated below th	e specified emission mask. The 0 dB	reference for the emission	on mask is the meas	ured output power of 24.7	dBm
RESULTS			AMPLITUDE			
Pass						
SIGNATURE						
Tested By:	ADU.K.P					
DESCRIPTION OF TEST	Т					
Occupied E	Bandwidth at Mid Cl	nannel - Mask C (25 k	Hz Channel Ba	andwidth E	quipment w/o A	udio Low

